

Kiessling, F.M.; Dropka, N.; Frank-Rotsch, Ch.; Kwapil, W.; Meyer, S.; Riepe, S.; Schmid, C.; Schumann, M., Influence of crucible quality on directionally solidified mc-Si ingot properties, *Poster at the Fourth European Conference on Crystal Growth* (2012) Glasgow, Scotland.

Schumann, M.; Meyer, S.; Schmid, C.; Haas, F.; Riepe, S.; Cröll, A., Impurity Control of Quartz Crucible Coatings for Directional Solidification of Silicon, *Proceedings of the 27th EU PVSEC*, 2012, 1049 – 1053.

Meißner, D.; Meyer, S.; Anspach, O., Enrichment of metal ions in virgin Si-surfaces, *Energy Procedia* 27 (2012) 27 – 32.

Kaufmann, K.;* Wahl, S.; Meyer, S.; Hagendorf, C., Quantitative elemental analysis of photovoltaic Cu(In,Ga)Se₂ thin films using MCs+ clusters, *Surf. Interface Anal.* 2013, 45, 434–436

Kwapil, W.; Zuschlag, A.; Reis, I.; Schwirtlich, I.; Meyer, S.; Zierer, R.; Krain, R.; Kießling, F.K.; Schumann, M.; Schmid, C.; Riepe, S., Influence of Crucible and Coating on the Contamination of Directionally Solidified Silicon: First Results of the German Research Network „SolarWinS“, *Proceedings of the 27th EU PVSEC*, 2012, 627 – 635.

Li, X.; Xiao, Y.; Bang, J.H.; Lausch, D.; Meyer, S.; Miclea, P.; Jung, J.; Schweizer, S.L.; Lee, J.; Wehrspohn R.B., Upgraded Silicon Nanowires by Metal-Assisted Etching of Metallurgical Silicon: A New Route to Nanostructured Solar-Grade Silicon, *Adv. Mater.* 25 (23), 2013, 3187–3191

Lauer, K.; Möller, C.; Neckermann, K.; Blecha, M.; Herms, M.; Mchedlidze, T.; Weber, J.; Meyer, S., Impact of a p-type solar cell process on the electrical quality of Czochralski silicon, *Energy Procedia* 38 (2013) 589 – 596.

Meyer, S.; Richter, S.; Timmel, S.; Gläser, M.; Werner, M.; Swatek, S.; Hagendorf C., Snail trails: root cause analysis and test procedures, *Energy Procedia* 38 (2013) 498 – 505.

Schubert, M.C.; Schön, J.; Schindler, F.; Kwapil, W.; Abdollahinia, A.; Michl, B.; Riepe, S.; Schmid, C.; Schumann, C.; Meyer, S.; Warta W., Impact of Impurities From Crucible and Coating on mc-Silicon Quality—the Example of Iron and Cobalt, *IEEE JOURNAL OF PHOTOVOLTAICS*, VOL. 3, NO. 4, (2013), 1250-58.

Karzel, P.; Ackermann, M.; Grömner, L.; Reimann, C.; Zschorsch, M.; Meyer, S.; Kiessling, F.; Riepe, S.; Hahn G., Dependence of phosphorus gettering and hydrogen passivation efficacy on grain boundary type in multicrystalline silicon, *JOURNAL OF APPLIED PHYSICS* 114, 244902 (2013),

Balski, M.; Kipphardt, H.; Berger, A.; Meyer, S.; Panne, U., Determination of impurities in solar grade silicon by inductively coupled plasma sector field mass spectrometry (ICP-SFMS) subsequent to matrix evaporation, *RSC Anal. Methods* 6 (2013), 77-85.

Meyer, S.; Timmel, S.; Richter, S.; Werner, M.; Gläser, M.; Swatek, S.; Braun, U.; Hagendorf, C., Silver nanoparticles cause snail trails in photovoltaic modules, *Solar Energy Materials & Solar Cells* 121(2014)171–175.

Meyer, S.; Timmel, S.; Gläser, M.; Braun, U.; Wachtendorf, V.; Hagendorf, C., Polymer foil additives trigger the formation of snail trails in photovoltaic modules, *Solar Energy Materials & Solar Cells* 130 (2014) 64–70.

Meyer, S.; Wahl, S.; Molchanov, A.; Neckermann, K.; Möller, C.; Lauer, K.; Hagendorf, C., Influence of the feedstock purity on the solar cell efficiency, *Solar Energy Materials & Solar Cells* 130 (2014) 668–672.

Meyer, S.; Timmel, S.; Hagendorf, C., Rapid determination of organic contaminations on wafer surfaces, *Solid State Phenomena* Vol. 219 (2015) 317-319

Meyer, S.; Timmel, S.; Braun, U.; Hagendorf, C., Polymer foil additives trigger the formation of snail trails in photovoltaic modules, *Energy Procedia* 55 (2014) 494 – 497.

D. Lausch, J. Hirsch, S. Wahl, S. Meyer, M. Gaudig, N. Bernhard, Analysis of Surface Contamination Levels Induced by Maskless Plasma Texturing of Silicon Solar Wafers, Proceedings of the 31st EU PVSEC, (2015)

K. Kaufmann, S. Wahl, S. Meyer, E. Jarzembowski, C. Hagendorf, Quantitative Analysis of Matrix Elements and Sodium in Photovoltaic Cu(In, Ga)Se₂ Thin Films by the Use of Time-of-Flight Secondary Ion Mass Spectrometry, Proceedings of the 31st EU PVSEC, (2015) 1256 – 1261.

S. Richter, S. Timmel, M. Gläser, D. Lausch, S. Meyer, C. Hagendorf, Correlative Microstructural Analysis and Determination of Local Grain Orientation of Multi-Crystalline Silicon Solar Cells, Proceedings of the 31st EU PVSEC, (2015).

S. Meyer, S. Wahl, S. Timmel, R. Köpge, B.-Y. Jang, The impact of wafering on organic and inorganic surface contaminations, Applied Surface Science 378 (2016) 384–387.

S. Wahl, S. Meyer, C. Hagendorf, Localization of inorganic impurities in silicon samples by sequential etching and ICP-MS detection, Energy Procedia 92 (2016) 392 – 398

S. Meyer, S. Wahl, C. Hagendorf, Advanced Metal Contamination Analysis for High Efficiency Solar Cell Manufacturing, Energy Procedia 92 (2016) 369 – 373.

Sakari Sintonen, Stefanie Wahl, Susanne Richter, Sylke Meyer, Sami Suihkonen, Tobias Schulz, Klaus Irmscher, Andreas N. Danilewsky, Turkka O. Tuomi, Romuald Stankiewicz, Martin Albrecht, Evolution of impurity incorporation during ammonothermal growth of GaN, Journal of Crystal Growth, Volume 456, 15 December 2016, Pages 51-57,

Turek, M.; Backhaus, A.; Meyer, S.; Seiffert, U.

Identification and classification of contaminations on wafers using hyperspectral imaging, Energy Procedia 2016 (2016) 232-235; 614/2016

Meyer, S., Turek, M., Großer, S., Manke, T., Hagendorf, C., Understanding snail trails on PV modules, PVTech Power, 10 (2017), 60-64.

Schütt, A., Wahl, S., Meyer, S., Hirsch, J., Lausch, D.: Fast large area reflectivity scans of wafers and solar cells with high spatial resolution, Energy Procedia 124 (2017) 166–173